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J. Douglas  
3/27/01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Blaine R. Spady, Robert Buchanan, and Richard A. Yarussi

Assignee: Nanometrics Incorporated

Title: System Using A Polar Coordinate Stage And Continuous Image Rotation To Compensate For Stage Rotation

Serial No.: 09/113,484 Filing Date: July 10, 1998

Examiner: R. Lee Group Art Unit: 2613

Docket No.: M-5955 US

San Jose, California  
March 19, 2001

BOX No Fee  
COMMISSIONER FOR PATENTS  
Washington, D. C. 20231

**RESPONSE TO OFFICE ACTION**

Dear Sir:

This is a response to the December 19, 2000 Office Action, which has a statutorily shortened period for response that ends March 19, 2001.

**IN THE SPECIFICATION**

Please replace the paragraph starting on page 1, line 23 with the following replacement paragraph.

The space required to accommodate the range of motion of an X,Y stage has a width that is equal to or greater than the width of the sample plus the travel distance in the X direction and a length that is equal to or greater than the length of the sample plus the travel distance in the Y direction. Fig. 1 illustrates a system 100 that uses an X,Y stage to position a circular sample 110. System 100 includes an imaging and/or measurement system (not shown) that can be, for example, a video camera, a microscope, an interferometer, a reflectometer, an ellipsometer, an FTIR spectrometer, or any type of spectrophotometer. Such systems typically have a field of view 130 that is much smaller than sample 110. To view the left edge of sample 110, the X,Y stage moves sample 110 to a position 112 where the left

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